

**Search Notes**

Application/Control No.

09/708,159

Examiner

J. Derek Rutten

Applicant(s)/Patent under  
Reexamination

YASUE ET AL.

Art Unit

2192

**SEARCHED**

| Class | Subclass | Date      | Examiner |
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| 717   | 148      | 1/12/2006 | JDR      |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE      | EXMR |
|---|-----------|------|
| ACM - portal.acm.org;<br>See search history printout                                | 1/5/2006  | JDR  |
| EAST (USPAT);<br>717/140-161 (text search only);<br>See search history printout     | 1/12/2006 | JDR  |
| ACM - portal.acm.org;<br>IEEE - ieeexplore.ieee.org;<br>See search history printout | 1/12/2006 | JDR  |
| EAST (USPAT)<br>See search history printout   | 1/17/2006 | JDR  |
| EAST (USPAT) - see search history<br>printout                                       | 1/18/2006 | JDR  |
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